TOSHIBA Photocoupler GaAlAs IRed & Photo-IC

TLP115

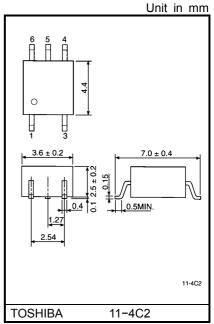
High Speed, Long Distance Isolated Line Receiver Microprocessor System Interfaces
Digital Isolation For A / D, D / A Conversion
Computer-Peripheral Interfaces
Ground Loop Elimination

The TOSHIBA mini flat coupler TLP115 is small outline coupler, suitable for surface mount assembly.

TLP115 consists of a GaAlAs light emitting diode, optically coupled to an integrated high gain, high speed shielded photo detector whose output is an open collector schottky clamped transistor.

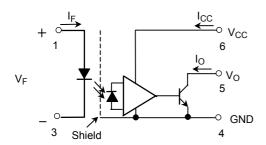
The shield, which shunts capacitively coupled common noise to ground, provides a guaranteed transient immunity specification of $1000V/\mu s$.

- Input current thresholds: IF=10mA (max.)
- Switching speed: 10MBd (typ.)
- Common mode transient immunity: ±1000V / μs (min.)
- Guaranteed performance over temp.: 0~70°C
- Isolation voltage: 2500Vrms (min.)
- UL recognized: UL1577, file no. E67349



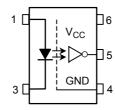
Weight: 0.09 g

Schematic



Note. A 0.1µF bypass capacitor must be connected between pins 4 and 6.

Pin Configuration(top view)



- 1 : Anode
- 3 : Cathode
- 4 : GND
- 5 : V_O(Output)
- 6 : V_{CC}

Truth Table(positive logic)

Input	Output
Н	L
L	Н

Maximum Ratings (Ta = 25°C)

	Characteristic		Symbol	Rating	Unit
LED	Forward current		IF	20	mA
	Pulse forward current	(Note 1)	I _{FP}	40	mA
	Peak transient forward current	(Note 2)	I _{FPT}	1	Α
	Reverse voltage		V _R	5	V
	Output current		IO	25	mA
ţo.	Output voltage		Vo	7	V
Detector	Supply voltage 1 minute maximum)		V _{CC}	7	٧
	Output power dissipation	ver dissipation		40	mW
Оре	Operating temperature range		T _{opr}	−40~85	°C
Storage temperature range		T _{stg}	−55~125	°C	
Lead solder temperature(10s)		T _{sol}	260	°C	
Isolation voltage (AC, 1min., RH ≤ 60%, Note 4)		BVS	2500	Vrms	

⁽Note 1) 50% duty cycle, 1ms pulse width.

Recommended Operating Conditions

Characteristic	Symbol	Min.	Тур.	Max.	Unit
Input voltage, low level	V_{FL}	-3	0	1.0	V
Input current, high level	I _{FH}	13	16	20	mA
Supply voltage	V _{CC}	4.5	5	5.5	V
Fan out (TTL load, each channel)	N	_	_	8	_
Operating temperature	T _{opr}	0	1	70	°C

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⁽Note 2) Pulse width ≤ 1µs, 300pps.

Electrical Characteristics (unless otherwise specified, Ta = 0~70°C, V_{CC} = 4.5~5.5V, $V_{FL} \le$ 1.0V)

Characteristic	Symbol	Test Condition	Min.	Typ.*	Max.	Unit	
Forward voltage	V _F	I _F =10mA, Ta=25°C	_	1.65	1.80	V	
Forward voltage temperature coefficient	V _F / Ta	I _F =10mA	_	-2	_	mV / °C	
Reverse current	I _R	V _R =5V, Ta=25°C	_	_	10	μA	
Capacitance between terminals	C _T	V _F =0, f=1MHz, Ta=25°C	_	45	_	pF	
Lligh lovel output ourrent	1	V _F =1.0, V _O =5.5V	_	_	250		
High level output current	Іон	V _F =1.0, V _O =5.5V, Ta=25°C	_	0.5	10	μΑ	
Low level output voltage	V _{OL}	I _F =10mA I _{OL} =13mA(sinking)	_	0.4	0.6	V	
"H level output→ L level output" input current	I _{FH}	I _{OL} =13mA(sinking) V _{OL} =0.6V	_	_	10	mA	
High level supply current	Icch	V _{CC} =5.5V, I _F =0	_	7	15	mA	
Low level supply current	ICCL	V _{CC} =5.5V, I _F =16mA	_	12	18	mA	
Input-output insulation leakage current	IS	V _S =3540V, t=5s Ta=25°C (Note 4)	_	_	100	μΑ	
Isolation resistance	R _S	R.H.≤ 60%, V _S =500V DC Ta=25°C (Note 4)	5×10 ¹⁰	10 ¹⁴	_	Ω	
Stray capacitance between input to output	CS	V _S =0, f=1MHz Ta=25°C (Note 4)	_	0.8	_	pF	

^{*} All typical values are V_{CC} =5V, Ta=25°C

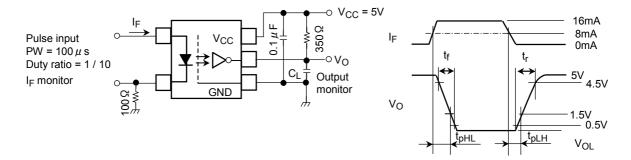
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Switching Characteristics($V_{CC} = 5V$, Ta = 25°C)

Characteristic	Symbol	Test Cir– cuit	Test Condition	Min.	Тур.	Max.	Unit
Propagation delay time (H→L)	t _{pHL}	1	$I_F=0 \rightarrow 16 \text{mA}$ $C_L=15 \text{pF}, R_L=350 \Omega$	-	60	120	ns
Propagation delay time (L→H)	t _{pLH}	1	$\begin{array}{l} I_{\text{F}}\text{=}16 \rightarrow 0 \text{mA} \\ C_{\text{L}}\text{=}15 \text{pF}, \ R_{\text{L}}\text{=}350 \Omega \end{array}$		60	120	ns
Output rise fall time (10–90%)	t _r , t _f	2	$R_L=350\Omega$, $C_L=15pF$ $I_F=0 \rightleftharpoons 16mA$	_	30	_	ns
Common mode transient immunity at high output level	CM _H	2	I_F =0mA, V_{CM} =400 V_{p-p} $V_{O(min)}$ =2V, R_L =350 Ω	1000		ı	V / µs
Common mode transient immunity at low output level	CML	2	$I_{\text{F}}\text{=}16\text{mA}, V_{\text{CM}}\text{=}400V_{\text{p-p}}$ $V_{\text{O(max)}}\text{=}0.8V,$ $R_{\text{L}}\text{=}350\Omega$	-1000	_	_	V / µs

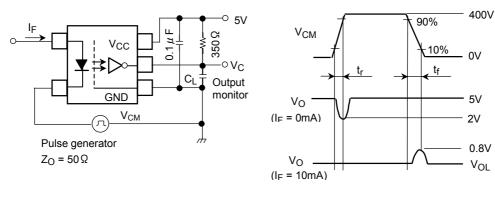
- (Note 4) Device considered a two-terminal device: Pins 1 and 3 shorted together, and pins 4, 5 and 6 shorted together.
- (Note 5) The V_{CC} supply voltage to each TLP115 isolator must be bypassed by $0.1\mu F$ capacitor. This can be either a ceramic or solid tantalum capacitor with good high frequency characteristic and should be connected as close as possible to package V_{CC} and GND pins of each device.
- (Note 6) Maximum electrostatic discharge voltage for any pins: 180V(C=200pF, R=0)

Test Circuit 1: Switching Time Test Circuit



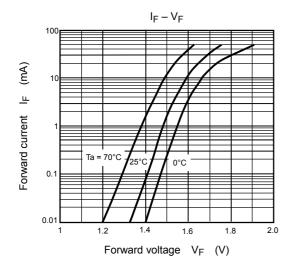
C_L is approximately 15pF which includes probe and stray wiring capacitance.

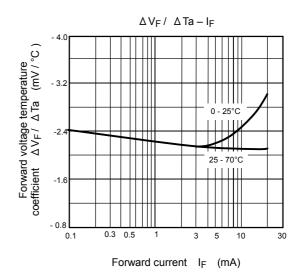
Test Circuit 2: Common Mode Transient Immunity Test Circuit

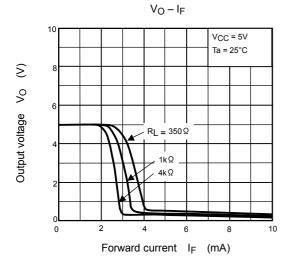


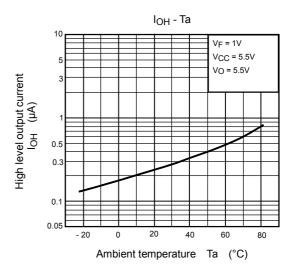
$$CM_{H}=\frac{320(V)}{t_{\Gamma}(\mu s)},CM_{L}=\frac{320(V)}{t_{f}(\mu s)}$$

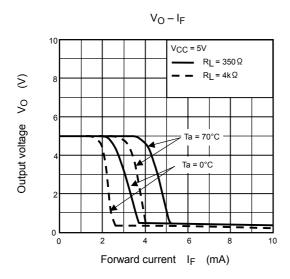
 C_L is approximately 15pF which includes probe and stray wiring capacitance.

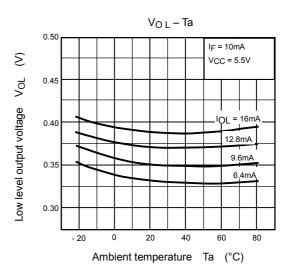


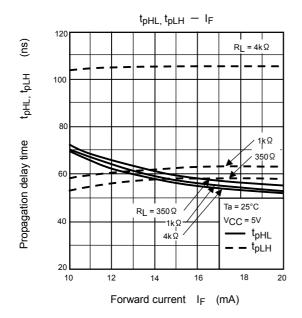


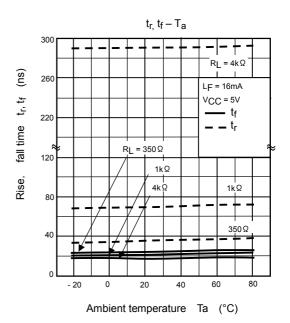


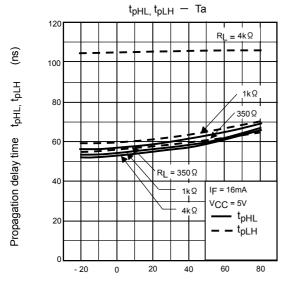












Ambient temperature Ta (°C)

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